

Search Notes

Application/Control No.

10/762,761

Examiner

David E. Bochna

Applicant(s)/Patent under
Reexamination

HAYASHI ET AL.

Art Unit

3679

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
285	415	3/3/2006	DB

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated the previous search	3/3/2006	DB